

Application/Control No. 10/779,842

Examiner
James A. Dudek

Applicant(s)/Patent under Reexamination

KIM ET AL.

Art Unit 2871

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	INTERNATIONAL CLASSIFICATION													
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(Assistant Examiner) (Date) Japan					A) Sude	k 7/2	0/07	Total Claims Allowed: 18					
					Examiner) (Date)				:	O.G. Print Claim(s)				
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	Claims renumbered in the same order as presented by applicant										☐ CPA			☐ T.D.			☐ R.1.47		
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1	1			31	·		61			91			121			151			181
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5	5			35		•	65			95			125			155			185
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7	7			37			67			97			127			157			187
8	8			38			68]		98			128			158			188
	9			39			69			99			129			159			189
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10	11			41			71]		101			131			161			191
11	12			42			72] .		102			132			162			192
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13	14			44			74]		104			134			164			194
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	26			56			86			116			146	, [176			206
	27			57	,		87]		117			147			177			207
	28			58			88	·		118			148			178			208
	29			59			89]		119			149			179			209
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